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Design and Evaluation of Secure Diagnosis and Control Benchmarks and Test-Scenarios for Cyber-Physical Systems

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Deadline for manuscript submissions:

closed (10 January 2022)

Message from the Guest Editors

Cyber-Physical Systems (CPS) integrate physical processes, computational resources, and communication capabilities. In this Special Issue, we invite authors to share their experience with the design of such benchmark cases and/or performing test scenarios of the developed algorithms.

- cyber-physical systems
- cloud computing
- industrial internet of things
- control as a service
- secure state estimation
- encrypted control
- cybersecurity
- fault-tolerant control
- resilient control
- cyber-attack detection
- cyber-attack mitigation
- industrial cyber-attack benchmarks

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Message from the Editor-in-Chief

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